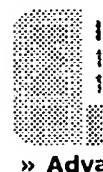


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L23	251182	(block\$6 or stop\$6 or etchstop\$6 or isolat\$6) near15 (light\$6 or optical\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/27 17:26
L27	42844	23 and (ARC or ARL or ARD or BARC or BARD or BARL or antireflect\$6 or (anti adj reflect\$6)or DARC or DARL or SiO2 or SiO?sub\$2 or SiN or Si3N4 or SiON or ((Si or silicon) adj (oxide or dioxide or nitride or oxynitride)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/27 17:33
L28	42844	27 and (ARC or ARL or ARD or BARC or BARD or BARL or antireflect\$6 or (anti adj reflect\$6)or DARC or DARL or SiO2 or SiO?sub\$2 or SiN or Si3N4 or SiON or ((Si or silicon) adj (oxide or dioxide or nitride or oxynitride)))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/27 17:33
L29	42277	28 and (@ad<="20031226" or @rlad<="20031226")	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/27 17:33
L30	12081	29 and (resist or photoresist or photolithograph\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/27 17:34
L31	8869	30 and semiconductor	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/27 17:34
L32	8707	31 and (pattern\$6 or etch\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/27 17:34
L33	1600	32 and (block\$6 or stop\$6 or etchstop\$6 or isolat\$6) same (polysilicon or polySi or (poly adj (Si or silicon)) or alumium or w or tungsten or al) same (light\$6 or optical\$6)	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2004/12/27 17:36

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Example: optical <and> (fiber <or> fibre) <in> ti
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 (light or optical) and
 (isolat* or absorb*) and
 (photo*) and (pattern* or
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